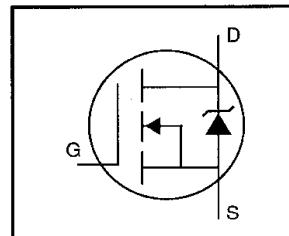


**HEXFET® Power MOSFET**

- Isolated Package
- High Voltage Isolation= 2.5KVRMS ⑤
- Sink to Lead Creepage Dist.= 4.8mm
- Dynamic dv/dt Rating
- Low Thermal Resistance
- Lead-Free

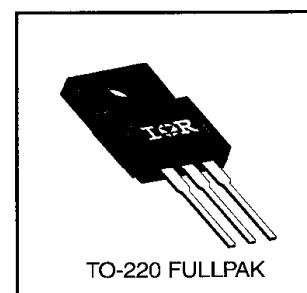


$V_{DSS} = 200V$   
 $R_{DS(on)} = 0.80\Omega$   
 $I_D = 4.1A$

**Description**

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 Fullpak eliminates the need for additional insulating hardware in commercial-industrial applications. The moulding compound used provides a high isolation capability and a low thermal resistance between the tab and external heatsink. This isolation is equivalent to using a 100 micron mica barrier with standard TO-220 product. The Fullpak is mounted to a heatsink using a single clip or by a single screw fixing.



**Absolute Maximum Ratings**

	Parameter	Max.	Units
$I_D @ T_c = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10 V$	4.1	
$I_D @ T_c = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10 V$	2.6	A
$I_{DM}$	Pulsed Drain Current ①	16	
$P_D @ T_c = 25^\circ C$	Power Dissipation	30	W
	Linear Derating Factor	0.24	W/ $^\circ C$
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$E_{AS}$	Single Pulse Avalanche Energy ②	100	mJ
$I_{AR}$	Avalanche Current ①	4.1	A
$E_{AR}$	Repetitive Avalanche Energy ①	3.0	mJ
$dv/dt$	Peak Diode Recovery $dv/dt$ ③	5.0	V/ns
$T_J$	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ C$
$T_{STG}$	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting Torque, 6-32 or M3 screw	10 lbf-in (1.1 N·m)	

**Thermal Resistance**

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	—	4.1	$^\circ C/W$
$R_{\theta JA}$	Junction-to-Ambient	—	—	65	

**Electrical Characteristics @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	200	—	—	V	$V_{GS}=0\text{V}$ , $I_D=250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	—	0.29	---	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}$ , $I_D=1\text{mA}$
$R_{DS(\text{on})}$	Static Drain-to-Source On-Resistance	—	—	0.80	$\Omega$	$V_{GS}=10\text{V}$ , $I_D=2.5\text{A}$ ④
$V_{GS(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS}=V_{GS}$ , $I_D=250\mu\text{A}$
$g_{fs}$	Forward Transconductance	1.5	—	—	S	$V_{DS}=50\text{V}$ , $I_D=2.5\text{A}$ ④
$I_{DS(\text{ss})}$	Drain-to-Source Leakage Current	—	—	25	$\mu\text{A}$	$V_{DS}=200\text{V}$ , $V_{GS}=0\text{V}$
		—	—	250		$V_{DS}=160\text{V}$ , $V_{GS}=0\text{V}$ , $T_J=125^\circ\text{C}$
$I_{GS(\text{ss})}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS}=20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS}=-20\text{V}$
$Q_g$	Total Gate Charge	—	—	14	nC	$I_D=4.8\text{A}$
$Q_{gs}$	Gate-to-Source Charge	—	—	3.0		$V_{DS}=160\text{V}$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge	—	—	7.9		$V_{GS}=10\text{V}$ See Fig. 6 and 13 ④
$t_{d(on)}$	Turn-On Delay Time	—	7.2	—	ns	$V_{DD}=100\text{V}$
$t_r$	Rise Time	—	22	—		$I_D=4.8\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	—	19	—		$R_G=18\Omega$
$t_f$	Fall Time	—	13	—		$R_D=20\Omega$ See Figure 10 ④
$L_D$	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6 mm (0.25in.) from package and center of die contact
$L_S$	Internal Source Inductance	—	7.5	—		
$C_{iss}$	Input Capacitance	—	260	—	pF	$V_{GS}=0\text{V}$
$C_{oss}$	Output Capacitance	—	100	—		$V_{DS}=25\text{V}$
$C_{rss}$	Reverse Transfer Capacitance	—	30	—		$f=1.0\text{MHz}$ See Figure 5
$C$	Drain to Sink Capacitance	—	12	—	pF	$f=1.0\text{MHz}$

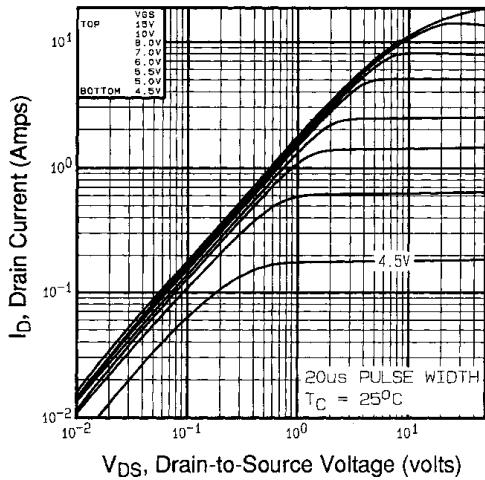
**Source-Drain Ratings and Characteristics**

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$I_s$	Continuous Source Current (Body Diode)	—	—	4.1	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode) ①	—	—	16		
$V_{SD}$	Diode Forward Voltage	—	—	1.8	V	$T_J=25^\circ\text{C}$ , $I_s=4.1\text{A}$ , $V_{GS}=0\text{V}$ ④
$t_{rr}$	Reverse Recovery Time	—	150	300	ns	$T_J=25^\circ\text{C}$ , $I_F=4.8\text{A}$
$Q_{rr}$	Reverse Recovery Charge	—	0.91	1.8	$\mu\text{C}$	$dI/dt=100\text{A}/\mu\text{s}$ ④
$t_{on}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S+L_D$ )				

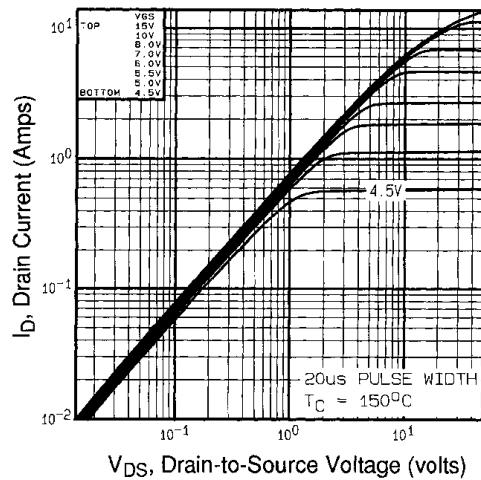
## Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature (See Figure 11)      ③  $I_{SD}\leq 5.2\text{A}$ ,  $dI/dt\leq 95\text{A}/\mu\text{s}$ ,  $V_{DD}\leq V_{(\text{BR})\text{DSS}}$ ,  $T_J\leq 150^\circ\text{C}$       ⑤  $t=60\text{s}$ ,  $f=60\text{Hz}$   
 ②  $V_{DD}=50\text{V}$ , starting  $T_J=25^\circ\text{C}$ ,  $L=8.9\text{mH}$       ④ Pulse width  $\leq 300 \mu\text{s}$ ; duty cycle  $\leq 2\%$ .  
 $R_G=25\Omega$ ,  $I_{AS}=4.1\text{A}$  (See Figure 12)

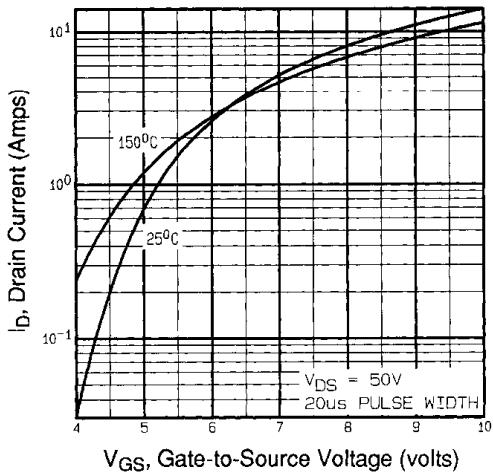
## IRFI620GPbF



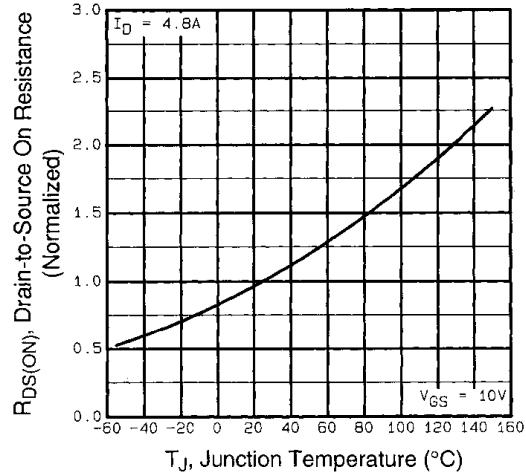
**Fig 1.** Typical Output Characteristics,  
 $T_C = 25^\circ\text{C}$



**Fig 2.** Typical Output Characteristics,  
 $T_C = 150^\circ\text{C}$



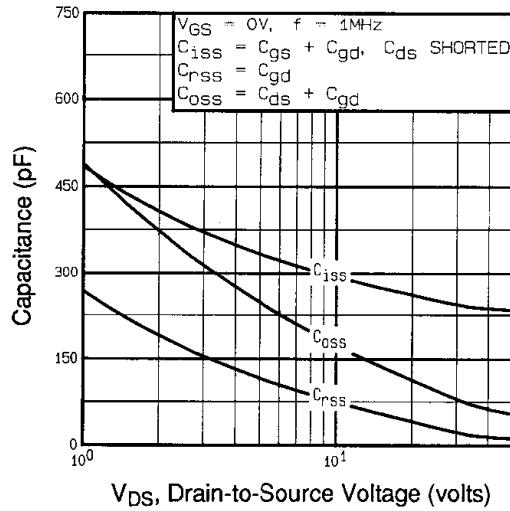
**Fig 3.** Typical Transfer Characteristics



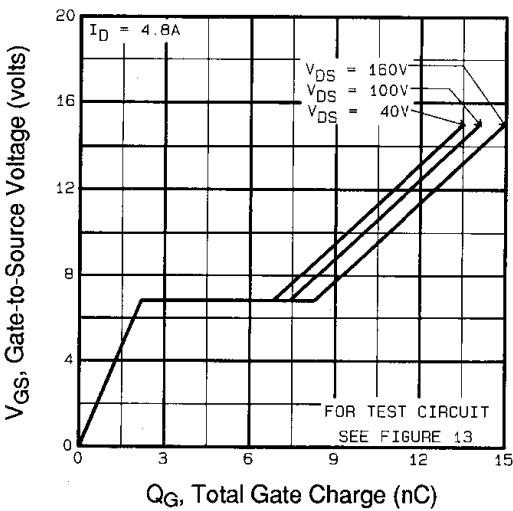
**Fig 4.** Normalized On-Resistance  
 Vs. Temperature

# IRFI620GPbF

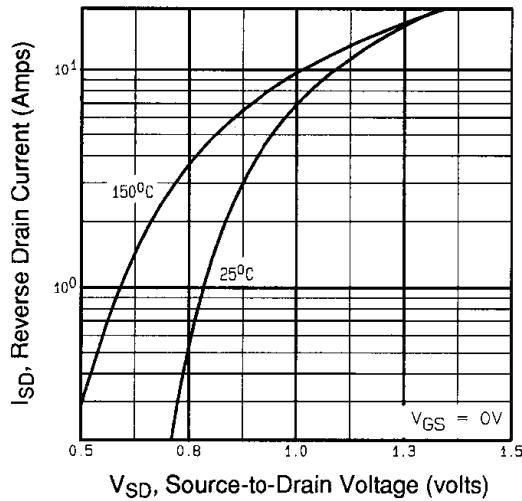
International  
**IR** Rectifier



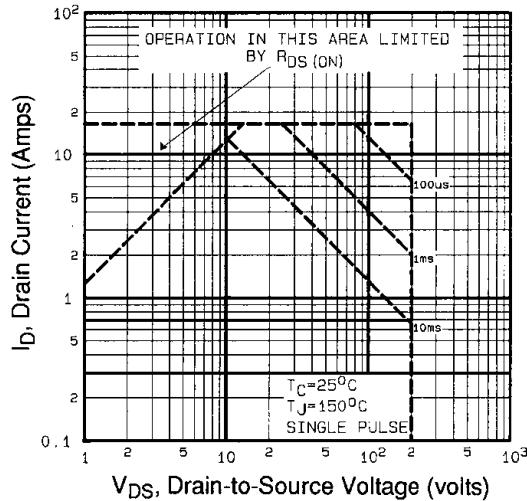
**Fig 5.** Typical Capacitance Vs.  
Drain-to-Source Voltage



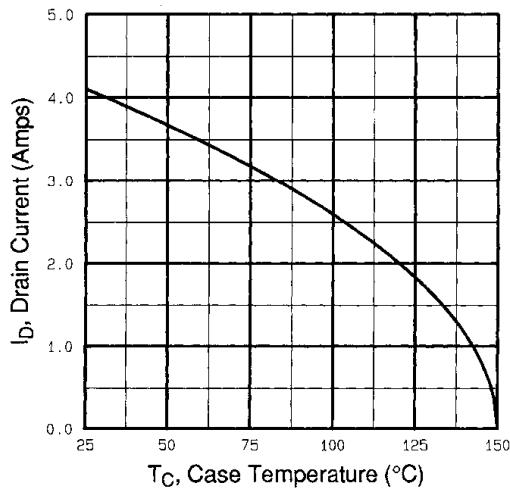
**Fig 6.** Typical Gate Charge Vs.  
Gate-to-Source Voltage



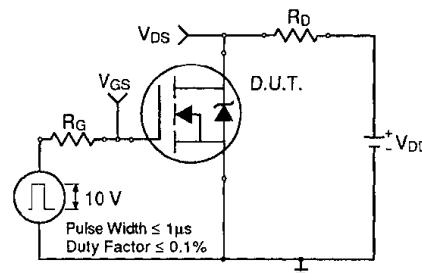
**Fig 7.** Typical Source-Drain Diode  
Forward Voltage



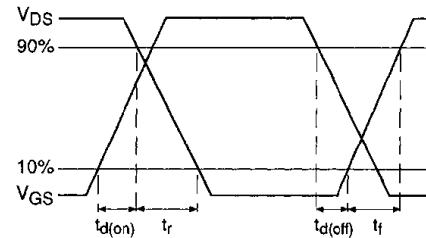
**Fig 8.** Maximum Safe Operating Area



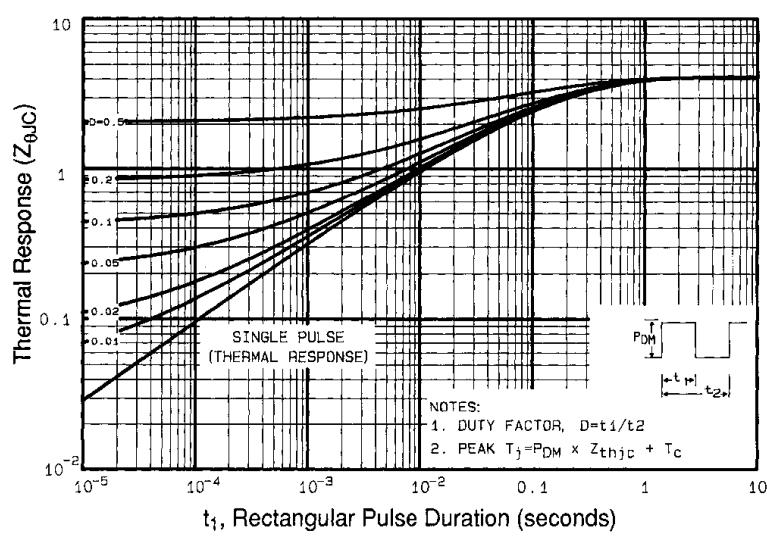
**Fig 9.** Maximum Drain Current Vs.  
Case Temperature



**Fig 10a.** Switching Time Test Circuit



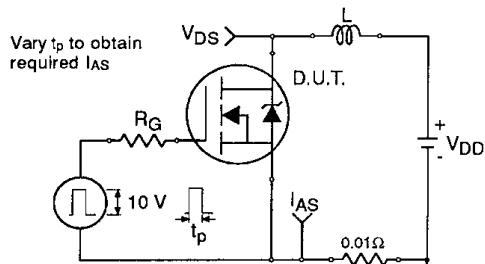
**Fig 10b.** Switching Time Waveforms



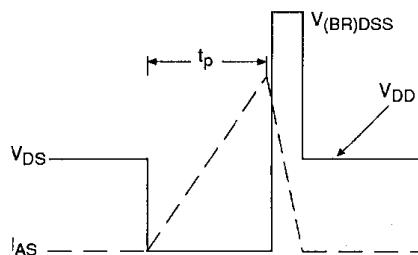
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case

# IRFI620GPbF

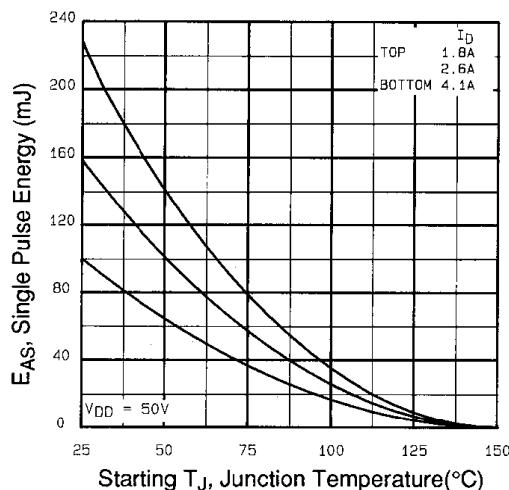
International  
**IR** Rectifier



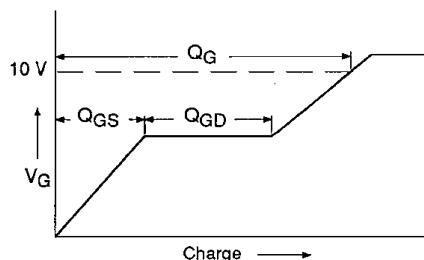
**Fig 12a.** Unclamped Inductive Test Circuit



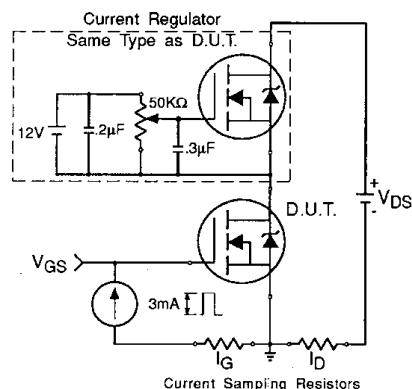
**Fig 12b.** Unclamped Inductive Waveforms



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

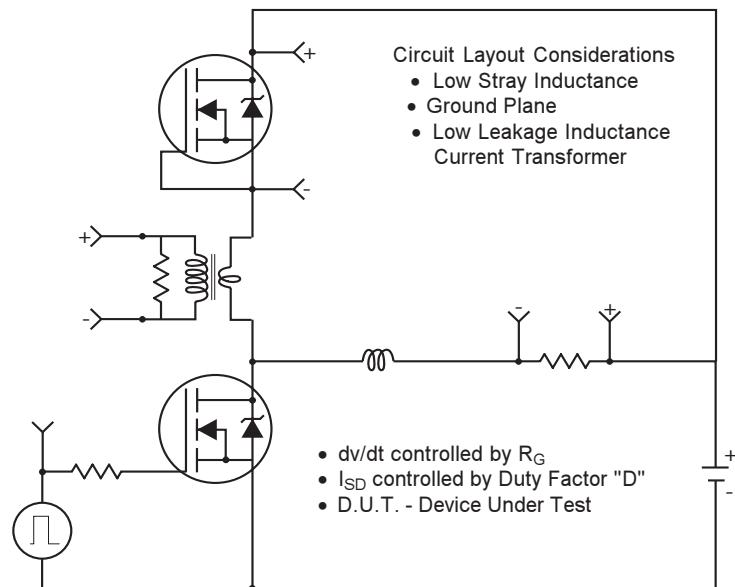


**Fig 13a.** Basic Gate Charge Waveform



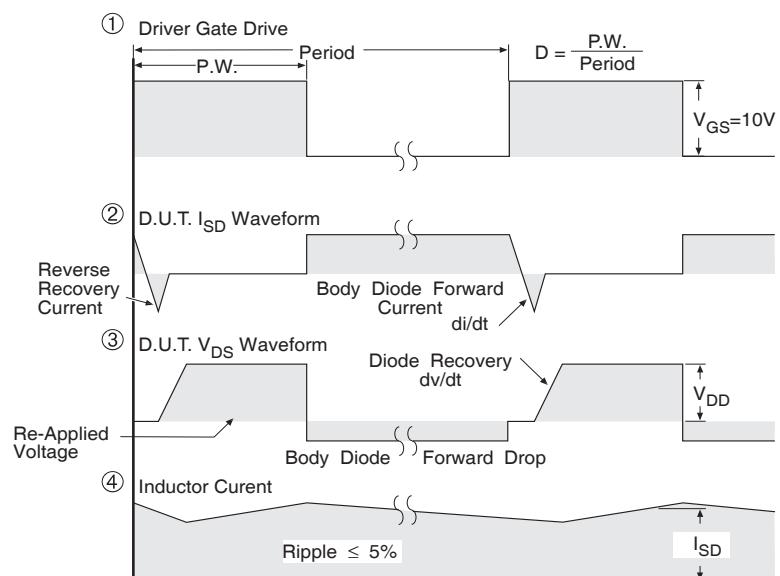
**Fig 13b.** Gate Charge Test Circuit

## Peak Diode Recovery dv/dt Test Circuit



\* Reverse Polarity for P-Channel

\*\* Use P-Channel Driver for P-Channel Measurements



\*\*\*  $V_{GS} = 5.0V$  for Logic Level and 3V Drive Devices

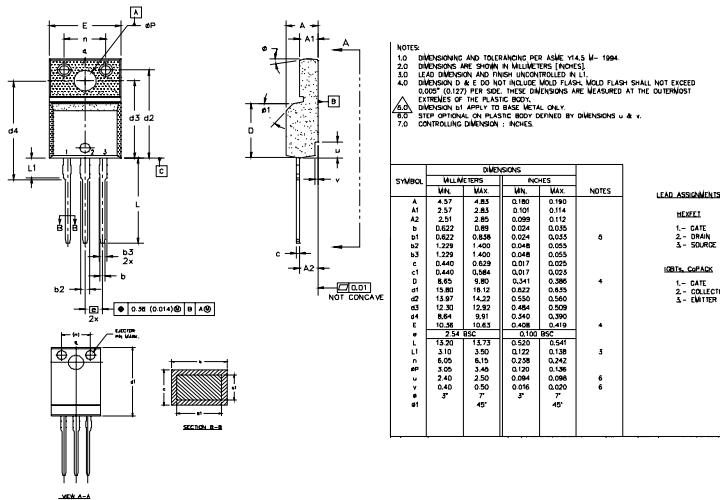
**Fig. 14** For N and P Channel HEXFETS

# IRFI620GPbF

International  
**IR** Rectifier

## TO-220 Full-Pak Package Outline

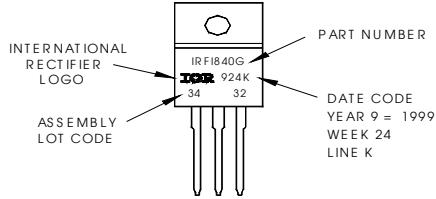
Dimensions are shown in millimeters (inches)



## TO-220 Full-Pak Part Marking Information

EXAMPLE: THIS IS AN IRFI840G  
WITH ASSEMBLY  
LOT CODE 3432  
ASSEMBLED ON WW 24 1999  
IN THE ASSEMBLY LINE "K"

Note: "P" in assembly line  
position indicates "Lead-Free"



Data and specifications subject to change without notice.

International  
**IR** Rectifier

IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105  
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